

Notice of References Cited	Application/Control No. 10/808,499		Applicant(s)/Patent Under Reexamination MIYAIRI ET AL.	
	Examiner Jeffrey R. West		Art Unit 2857	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0016349	01-2003	Tsumura et al.	356/237.2
*	B	US-2002/0031249	03-2002	Komuro et al.	382/149
*	C	US-2005/0041226	02-2005	Tanaka et al.	355/053
*	D	US-2004/0228526	11-2004	Lin et al.	382/165
*	E	US-2003/0142298	07-2003	Ujihara et al.	356/237.2
*	F	US-6,861,614	03-2005	Tanabe et al.	219/121.66
*	G	US-6,051,834	04-2000	Kakibayashi et al.	250/311
*	H	US-2002/0059896	05-2002	Yamaguchi et al.	117/7
*	I	US-2004/0203219	10-2004	Kasahara et al.	438/487
*	J	US-5,835,614	11-1998	Aoyama et al.	382/104
*	K	US-5,091,963	02-1992	Litt et al.	382/149
*	L	US-6,836,532	12-2004	Durst et al.	378/73
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 2000114174 A	04-2000	Japan	ABE, HIROYUKI	H01L 21/20
*	O	JP 2000031229 A	01-2000	Japan	TERADA, SHIGEKI	G01J 3/42
*	P	JP 2002217107 A	08-2002	Japan	WADA et al.	H01L 21/66
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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